



A One-Day Workshop on

***In-Situ Transmission  
Electron Microscopy  
in Materials Science***

presented by

**Midwest Microscopy and Microanalysis Society (M<sup>3</sup>S)**

A local affiliate of the Microscopy Society of America  
and the Microbeam Analysis Society

Friday October 29<sup>th</sup>, 2010

BP – Naperville Center  
150 W Warrenville Rd  
Naperville, IL 60563

**Please RSVP by Friday, October, 22<sup>nd</sup>**

Email your contact information to:

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***Onsite Registration Fee:***

Free to M<sup>3</sup>S members, \$20.00 for non-members, \$5.00 for students  
(M<sup>3</sup>S membership for 2011 included in fee)  
Lunch is included.

We welcome vendor participation. Tables for literature and exhibits will be available. Please contact us for details.

## ***Program Schedule:***

- 08:00 – 08:45 Registration
- 08:45 – 09:00 Opening remarks / Safety Video
- 09:00 – 09:45 **MSA-LAS Tour Speaker, Grace Burke**, Bechtel Bettis, Inc. – *‘Real World Microscopy: Applications of FIB to the Analysis of Real Materials’*
- 09:45 – 10:15 **Ian Robertson**, University of Illinois at Urbana-Champaign – *‘Three-dimensional Time-Resolved Studies of Defect Behavior – Current Status and Future Directions’*
- 10:15 – 10:45 Coffee Break / Exhibits
- 10:45 – 11:15 **John Regalbuto**, University of Illinois at Chicago – *‘Electron Microscopy for Fundamental Studies of Catalyst Synthesis’*
- 11:15 – 11:45 **Stephen Mick**, Protochips Inc. – *‘A Semiconductor Platform for High Resolution in situ Electron Microscopy’*
- 11:45 – 12:15 **Reza Shahbazian-Yassar**, Michigan Technological University – *‘In-Situ Electrical-Mechanical-Thermal Characterization of Inorganic Nanowires and Nanotubes’*
- 12:15 – 13:30 Lunch / Exhibits
- 13:30 – 14:00 **Eric Stach**, Purdue University – *‘Exploiting UHV and Environmental Microscopy to Understand Nucleation and Growth of Semiconductor Nanowires’*
- 14:00 – 14:30 **Oden Warren**, Hysitron Inc. – *‘Advanced Nanomechanical Test Instrument for the Transmission Electron Microscope’*
- 14:30 – 14:45 Break
- 14:45 – 15:15 **Xiaoqing Pan**, University of Michigan at Ann Arbor – *To be announced*
- 15:15 – 15:45 **Laurence Marks**, Northwestern University – *‘Friction in Full View’*
- 15:45 – 16:15 **Marija Gajdardziska-Josifovska**, University of Wisconsin-Milwaukee – *To Be Announced*
- 16:15 – 16:25 **Dean Miller**, Argonne National Laboratory – *‘iTEAM: the in situ Transmission Electron Aberration Corrected Microscope’*